

Notice of References Cited	Application/Control No. 10/727,775	Applicant(s)/Patent Under Reexamination KLEIN ET AL.	
	Examiner Christopher B. Shin	Art Unit 2182	Page 1 of 1

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*	E	US-6,487,561	11-2002	Ofek et al.	707/204
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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